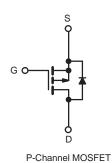


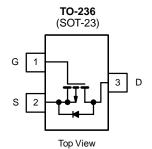
P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	- 60			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = - 10 V	0.04		
Q _g (Max.) (nC)	12			
Q _{gs} (nC)	3.8			
Q _{gd} (nC)	5.1			
Configuration	Single			

FEATURES

- Isolated Package
- High Voltage Isolation = $2.5 \text{ kV}_{\text{RMS}}$ (t = 60 s; f = 60 Hz
- Sink to Lead Creepage Distance = 4.8 mm
- P-Channel
- 175 °C Operating Temperature
- Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available





ABSOLUTE MAXIMUM RATINGS T	$_{\rm C}$ = 25 °C, unless otherw	ise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	- 60	v	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current	$V_{GS} \text{ at - 10 V} \frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$	I _D -	- 5.2		
Continuous Drain Current			- 3.8	А	
Pulsed Drain Current ^a	I _{DM}	- 21			
Linear Derating Factor			0.18	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	120	mJ	
Repetitive Avalanche Current ^a		I _{AR}	- 5.2	А	
Repetitive Avalanche Energy ^a		E _{AR}	2.7	mJ	
Maximum Power Dissipation	T _C = 25 °C	PD	27	W	
Peak Diode Recovery dV/dt ^c		dV/dt	- 4.5	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	- °C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf · in	
	0-52 OF MIS SCIEW	-	1.1	N·m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = -25$ V, starting $T_J = 25$ °C, L = 5.0 mH, $R_G = 25 \Omega$, $I_{AS} = -5.3$ A (see fig. 12). c. $I_{SD} \le -6.7$ A, dI/dt ≤ 90 A/µs, $V_{DD} \le V_{DS}$, $T_J \le 175$ °C.

d. 1.6 mm from case.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP	•	MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		65		2041/		
Maximum Junction-to-Case (Drain)	R _{thJC}	- 5.5			°C/W			
		÷						
SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	unless otherw	vise noted						
PARAMETER	SYMBOL	TES	T CONDITI	ONS	MIN.	TYP.	MAX.	UNIT
Static								
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	0 V, I _D = - 2	250 µA	- 60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I	_D = - 1 mA	-	- 0.060	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} =$	V_{GS} , $I_D = -2$	250 µA	- 1.0	-	- 2.5	V
Gate-Source Leakage	I _{GSS}	N	/ _{GS} = ± 20 '	V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =	- 60 V, V _{GS}	₆ = 0 V	-	-	- 100	μA
Zero Gale Voltage Drain Gurrent	DSS	V _{DS} = - 48	$V_{GS} = 0 V,$	T _J = 150 °C	-	-	- 500	μΛ
Drain-Source On-State Resistance	R _{DS(on)}	V_{GS} = - 10 V	I _D =	= - 3.2 A ^b	-	0.05	-	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = -$	25 V, I _D =	- 3.2 A ^b	1.6	-	-	S
Dynamic								
Input Capacitance	Ciss		$V_{GS} = 0 V$,		-	270	-	
Output Capacitance	C _{oss}	V _{DS} = - 25 V, f = 1.0 MHz, see fig. 5 f = 1.0 MHz		-	170	-	рF	
Reverse Transfer Capacitance	C _{rss}			-	31	-		
Drain to Sink Capacitance	С			-	12	-		
Total Gate Charge	Qg				-	-	12	
Gate-Source Charge	Q _{gs}	$V_{GS} = -10 \text{ V}$ $I_D = -4.7 \text{ A}, V_{DS} = -48 \text{ V},$ see fig. 6 and 13 ^b		-	-	3.8	nC	
Gate-Drain Charge	Q _{gd}		,	, 	-	-	5.1	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = -30 \text{ V}, \text{ I}_{D} = -4.7 \text{ A}, \\ \text{R}_{G} = 24 \Omega, \text{ R}_{D} = 4.0 \Omega, \\ \text{see fig. } 10^{\text{b}}$		-	11	-	ns	
Rise Time	t _r			-	63	-		
Turn-Off Delay Time	t _{d(off)}			-	9.6	-		
Fall Time	t _f			-	31	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	Ls			-	7.5	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	١ _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 5.2	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	- 21		
Body Diode Voltage	V _{SD}	$T_J = 25 \ ^\circ C, \ I_S = - \ 5.2 \ A, \ V_{GS} = 0 \ V^b$		-	-	- 5 .5	V	
Body Diode Reverse Recovery Time	t _{rr}	T ₁ = 25 °C I= -	474 di	/dt = 100 A/µs ^b	-	80	160	ns
Body Diode Reverse Recovery Charge	Q _{rr}	1 J – 20 O, IF	- . , A, ui	/ut = 100 A/µs ²	-	0.096	0.19	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time i	s negligible (turn-	on is dor	ninated by	/ L _S and L	_D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

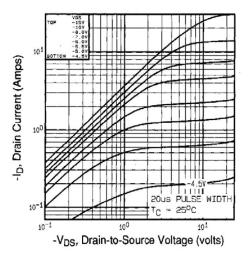


Fig. 1 - Typical Output Characteristics, T_C= 25 °C

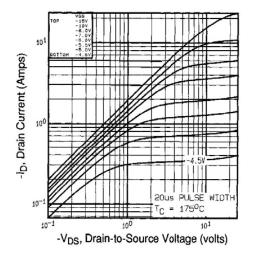


Fig. 2 - Typical Output Characteristics, T_C = 175 °C

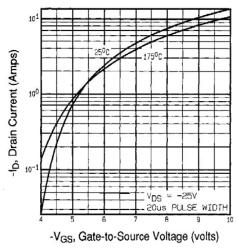


Fig. 3 - Typical Transfer Characteristics

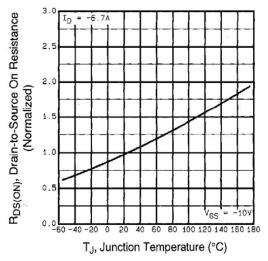


Fig. 4 - Normalized On-Resistance vs. Temperature

SI2309DS



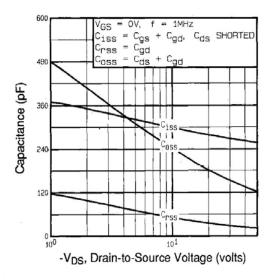


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

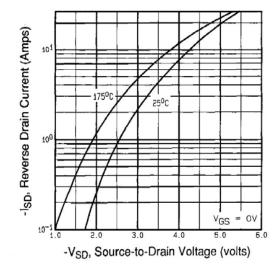


Fig. 7 - Typical Source-Drain Diode Forward Voltage

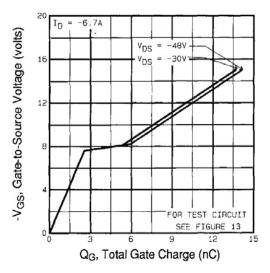


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

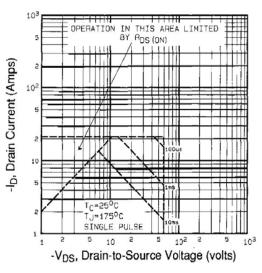


Fig. 8 - Maximum Safe Operating Area



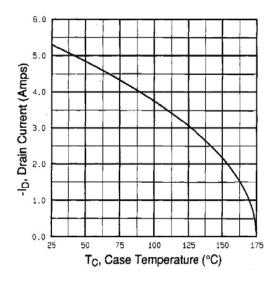


Fig. 9 - Maximum Drain Current vs. Case Temperature

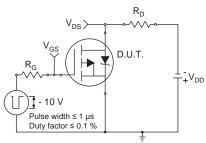


Fig. 10a - Switching Time Test Circuit

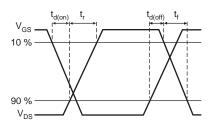
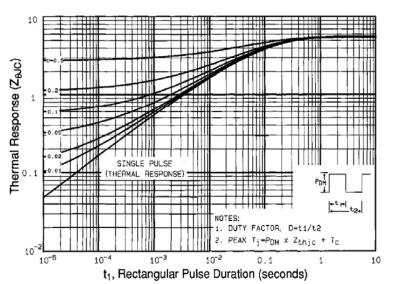


Fig. 10b - Switching Time Waveforms





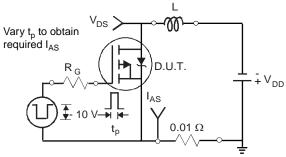


Fig. 12a - Unclamped Inductive Test Circuit

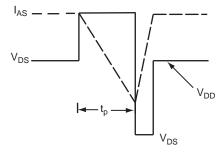
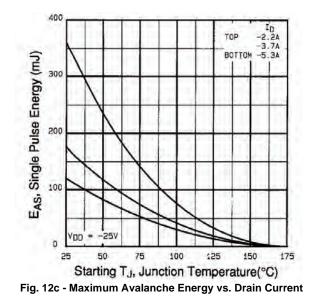
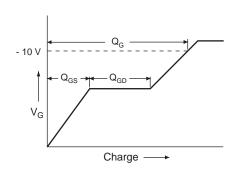


Fig. 12b - Unclamped Inductive Waveforms









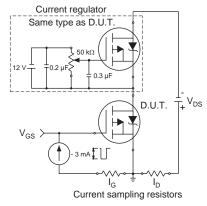
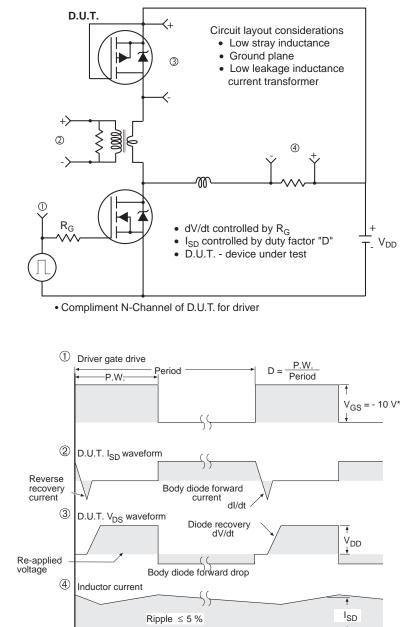
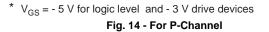


Fig. 13b - Gate Charge Test Circuit



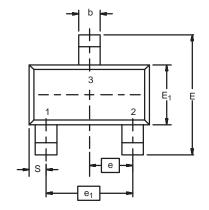


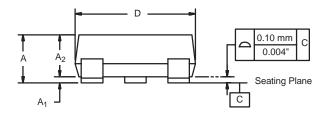
Peak Diode Recovery dV/dt Test Circuit

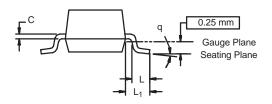




SOT-23 (TO-236): 3-LEAD



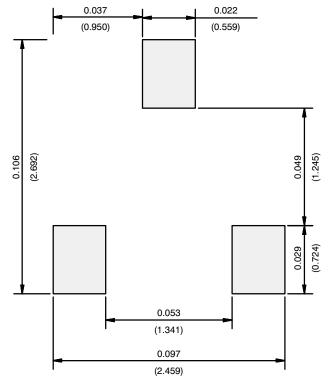




Dim	MILLIMETERS		INCHES		
	Min	Max	Min	Мах	
Α	0.89	1.12	0.035	0.044	
A ₁	0.01	0.10	0.0004	0.004	
A ₂	0.88	1.02	0.0346	0.040	
b	0.35	0.50	0.014	0.020	
С	0.085	0.18	0.003	0.007	
D	2.80	3.04	0.110	0.120	
E	2.10	2.64	0.083	0.104	
E ₁	1.20	1.40	0.047	0.055	
е	0.95 BSC		0.0374 Ref		
e ₁	1.90 BSC		0.0748 Ref		
L	0.40	0.60	0.016	0.024	
L ₁	0.64 Ref		0.025 Ref		
S	0.50 Ref		0.020 Ref		
q	3°	8°	3°	8°	



RECOMMENDED MINIMUM PADS FOR SOT-23



Recommended Minimum Pads Dimensions in Inches/(mm)



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